MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data sheet



Semiconductor





SOT-523

1. BASE

2. EMITTER

3. COLLECTOR

TRANSISTOR (PNP)

MMBT3906T-MS

FEATURES

- Epitaxial Planar Die Construction
- Complementary NPN Type Available
- Also Available in Lead Free Version

MARKING:3N

MAXIMUM RATINGS (T_a=25℃ unless otherwise noted)

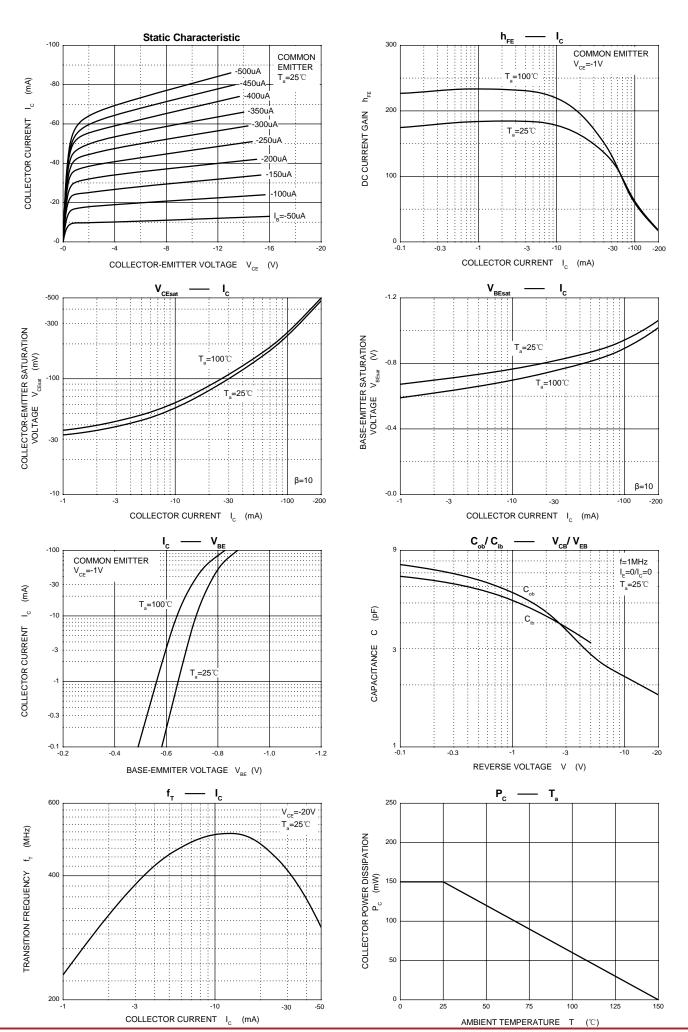
Symbol	Parameter	Value	Units
V _{CBO}	Collector-Base Voltage	-40	V
V _{CEO}	Collector-Emitter Voltage	-40	V
V _{EBO}	Emitter-Base Voltage	-5.0	V
Ic	Collector Current -Continuous	-200	mA
Pc	Collector Power Dissipation	150	mW
Reja	Thermal Resistance, Junction to Ambient		°C/W
T _J ,T _{stg}	Operation Junction and Storage Temperature Range	-55-150	${\mathfrak C}$

ELECTRICAL CHARACTERISTICS(Ta=25°C unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V _{(BR)CBO}	I _C =-10μΑ,I _E =0	-40			V
Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C =-1mA,I _B =0	-40			V
Emitter-base breakdown voltage	V _{(BR)EBO}	I _E =-10μΑ,I _C =0	-5			V
Collector cut-off current	I _{CBO}	V _{CB} =-40V,I _E =0			-0.1	μA
Emitter cut-off current	I _{EBO}	V _{EB} =-5V,I _C =0			-0.1	μΑ
Collector cut-off current	I _{CEX}	V _{CB} =-30V,V _{BE(off)} =-3V			-0.05	μΑ
	h _{FE(1)}	V _{CE} =-1V,I _C =-0.1mA	60			
	h _{FE(2)}	V _{CE} =-1V,I _C =-1mA	80			
DC current gain	h _{FE(3)}	V _{CE} =-1V,I _C =-10mA	100		300	
	h _{FE(4)}	V _{CE} =-1V,I _C =-50mA	60			
	h _{FE(5)}	V _{CE} =-2V,I _C =-100mA	30			
Collector-emitter saturation voltage	V _{CE(sat)1}	I _C =-10mA,I _B =-1mA			-0.25	>
Conector-entitler saturation voitage	V _{CE(sat)2}	I _C =-50mA,I _B =-5mA			-0.4	٧
Base-emitter saturation voltage	V _{BE(sat)1}	I _C =-10mA,I _B =-1mA	-0.65		-0.85	٧
Base-emitter saturation voltage	V _{BE(sat)2}	I _C =-50mA,I _B =-5mA			-0.95	٧
Transition frequency	f⊤	V _{CE} =-20V,I _C =-10mA,f=100MHz	250			MHz
Collector output capacitance	C_{obo}	V_{CB} =-5 V , I_E =0, f =1 MHz			4.5	pF
Input capacitance	C _{iob}	V _{EB} =-0.5V,I _E =0,f=1MHz			10	pF
Noise figure	NF	V_{CE} =-5V, I_{c} =0.1mA,			4	dB
Delay time	t _d	V_{CC} =-3V, $V_{BE(OFF)}$ =-0.5V			35	nS
Rise time	tr	I _C =-10mA , I _{B1} =-1mA			35	nS
Storage time	t _S	V _{CC} =-3V, I _C =-10mA			225	nS
Fall time	t _f	$I_{B1}=I_{B2}=-1mA$			75	nS

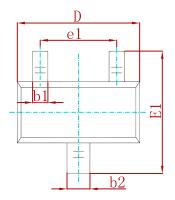
Semiconductor

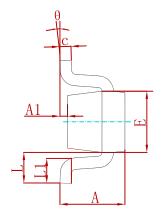
Compiance

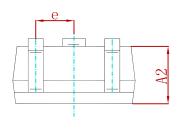




PACKAGE MECHANICAL DATA

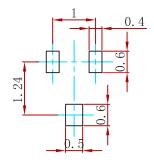






Comple ed	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	0.700	0.900	0.028	0.035	
A1	0.000	0.100	0.000	0.004	
A2	0.700	0.800	0.028	0.031	
b1	0.150	0.250	0.006	0.010	
b2	0.250	0.350	0.010	0.014	
С	0.100	0.200	0.004	0.008	
D	1.500	1.700	0.059	0.067	
Е	0.700	0.900	0.028	0.035	
E1	1.450	1.750	0.057	0.069	
е	0.500	TYP.	0.020	TYP.	
e1	0.900	1.100	0.035	0.043	
L	0.400	REF.	0.016	REF.	
L1	0.260	0.460	0.010	0.018	
θ	0°	8°	0°	8°	

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
MMBT3906T-MS	SOT-523	3000



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